Features

- Fast Read Access Time 70 ns
- Low Power CMOS Operation
 - 100 µA Max Standby
- 30 mA Max Active at 5 MHz
- JEDEC Standard Packages
 - 32-lead PDIP
 - 32-lead PLCC
 - 32-lead TSOP
- 5V \pm 10% Supply
- High Reliability CMOS Technology
 - 2000V ESD Protection
 - 200 mA Latchup Immunity
- Rapid Programming Algorithm 100 µs/Byte (Typical)
- CMOS and TTL Compatible Inputs and Outputs
- Industrial Temperature Range
- Green (Pb/Halide-free) Packaging Option

1. Description

The AT27C040 chip is a low-power, high-performance, 4,194,304-bit one-time programmable read-only memory (OTP EPROM) organized as 512K by 8 bits. The AT27C040 requires only one 5V power supply in normal read mode operation. Any byte can be accessed in less than 70 ns, eliminating the need for speed reducing WAIT states on high-performance microprocessor systems.

Atmel's scaled CMOS technology provides low active power consumption, and fast programming. Power consumption is typically 8 mA in active mode and less than 10 μ A in standby mode.

The AT27C040 is available in a choice of industry-standard JEDEC-approved onetime programmable (OTP) plastic PDIP, PLCC and TSOP packages. The device features two-line control (\overline{CE} , \overline{OE}) to eliminate bus contention in high-speed systems.

Atmel's AT27C040 has additional features to ensure high quality and efficient production use. The Rapid Programming Algorithm reduces the time required to program the part and guarantees reliable programming. Programming time is typically only 100 μ s/byte. The Integrated Product Identification Code electronically identifies the device and manufacturer. This feature is used by industry-standard programming equipment to select the proper programming algorithms and voltages.



4-Megabit (512K x 8) OTP EPROM

AT27C040

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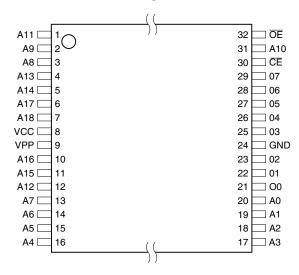
2. Pin Configurations

Pin Name	Function
A0 - A18	Addresses
00 - 07	Outputs
CE	Chip Enable
ŌE	Output Enable

			_
	\bigcirc		
1		32	b vcc
2		31	🗆 A18
3		30	🗆 A17
4		29	🗆 A14
5		28	🗆 A13
6		27	🗆 A8
7		26	🗆 A9
8		25	🗆 A11
9		24	D OE
10		23	🗆 A10
11		22	
12		21	07
13		20	06
14		19	05
15		18	04
16		17	03
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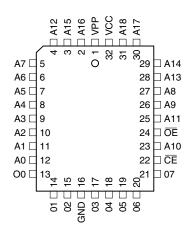
2.1 32-lead PDIP Top View

2.2 32-lead TSOP Top View



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2.3 32-lead PLCC Top View



AT27C040

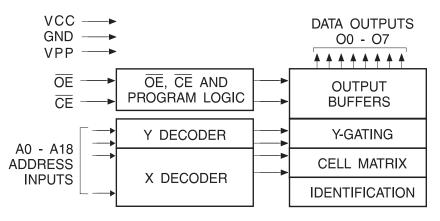
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3. Switching Considerations

Switching between active and standby conditions via the Chip Enable pin may produce transient voltage excursions. Unless accommodated by the system design, these transients may exceed datasheet limits, resulting in device non-conformance. At a minimum, a 0.1 μ F high frequency, low inherent inductance, ceramic capacitor should be utilized for each device. This capacitor should be connected between the V_{CC} and Ground terminals of the device, as close to the device as possible. Additionally, to stabilize the supply voltage level on printed circuit boards with large EPROM arrays, a 4.7 μ F bulk electrolytic capacitor should be utilized, again connected between the V_{CC} and Ground terminals. This capacitor should be positioned as close as possible to the point where the power supply is connected to the array.

4. Block Diagram



5. Absolute Maximum Ratings*

V _{PP} Supply Voltage with Respect to Ground2.0V to +14.0V
Voltage on A9 with Respect to Ground2.0V to +14.0V
Voltage on Any Pin with Respect to Ground2.0V to +7.0V
Storage Temperature65°C to +150°C
Temperature Under Bias

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*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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6. Operating Modes

Mode/Pin	CE	ŌĒ	Ai	V _{PP}	Outputs
Read	V _{IL}	V _{IL}	Ai	X ⁽¹⁾	D _{OUT}
Output Disable	Х	V _{IH}	Х	Х	High Z
Standby	V _{IH}	Х	Х	Х	High Z
Rapid Program ⁽²⁾	V _{IL}	V _{IH}	Ai	V _{PP}	D _{IN}
PGM Verify	Х	V _{IL}	Ai	V _{PP}	D _{OUT}
PGM Inhibit	V _{IH}	V _{IH}	Х	V _{PP}	High Z
Product Identification ⁽⁴⁾	V _{IL}	V _{IL}	$A9 = V_{H}^{(3)}$ $A0 = V_{IH} \text{ or } V_{IL}$ $A1 - A18 = V_{IL}$	х	Identification Code

Notes: 1. X can be V_{IL} or V_{IH} .

2. Refer to Programming Characteristics

- 3. $V_{H} = 12.0 \pm 0.5 V.$
- Two identifier bytes may be selected. All Ai inputs are held low (V_{IL}), except A9 which is set to V_H and A0 which is toggled low (V_{IL}) to select the Manufacturer's Identification byte and high (V_{IH}) to select the Device Code byte.

7. DC and AC Operating Conditions for Read Operation

	AT27C040-70	AT27C040-90
Industrial Operating Temperature (Case)	-40°C - 85°C	-40°C - 85°C
V _{CC} Power Supply	5V ± 10%	5V ±10%

8. DC and Operating Characteristics for Read Operation

Symbol	Parameter	Condition	Min	Max	Units
ILI	Input Load Current	$V_{IN} = 0V$ to V_{CC}		±1	μA
I _{LO}	Output Leakage Current	$V_{OUT} = 0V$ to V_{CC}		±5	μA
I _{PP1} ⁽²⁾	V _{PP} ⁽¹⁾ Read/Standby Current	V _{PP} = V _{CC}		10	μA
		I_{SB1} (CMOS), $\overline{CE} = V_{CC} \pm 0.3V$		100	μA
I _{SB} V _{CC1} ⁽¹⁾ Standby Current	I_{SB2} (TTL), \overline{CE} = 2.0 to V_{CC} + 0.5V		1	mA	
I _{CC}	V _{CC} Active Current	$f = 5 \text{ MHz}, I_{OUT} = 0 \text{ mA}, \overline{CE} = V_{IL}$		30	mA
V _{IL}	Input Low Voltage		-0.6	0.8	V
V _{IH}	Input High Voltage		2.0	V _{CC} + 0.5	V
V _{OL}	Output Low Voltage	I _{OL} = 2.1 mA		0.4	V
V _{OH}	Output High Voltage	I _{OH} = -400 μA	2.4		V

Notes: 1. V_{CC} must be applied simultaneously or before V_{PP} and removed simultaneously or after V_{PP}

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2. V_{PP} may be connected directly to V_{CC}, except during programming. The supply current would then be the sum of I_{CC} and I_{PP}

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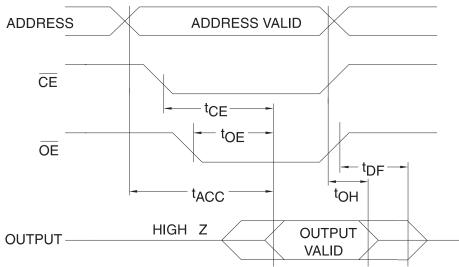
AT27C040

9. AC Characteristics for Read Operation

			-	70	-!	90	
Symbol	Parameter	Condition	Min	Max	Min	Max	Units
t _{ACC} ⁽¹⁾	Address to Output Delay	$\overline{CE} = \overline{OE} \\ = V_{IL}$		70		90	ns
t _{CE} ⁽¹⁾	CE to Output Delay	$\overline{OE} = V_{IL}$		70		90	ns
t _{OE} ⁽¹⁾	OE to Output Delay	$\overline{CE} = V_{IL}$		30		35	ns
t _{DF} ⁽¹⁾	OE or CE High to Output Float, Whichever Occurred First			20		20	ns
t _{OH}	Output Hold from Address, CE or OE, Whichever Occurred First		0		0		ns

Note: 1. See AC Waveforms for Read Operation

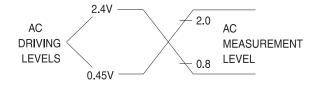
10. AC Waveforms for Read Operation⁽¹⁾



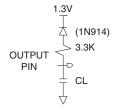
- Notes: 1. Timing measurement references are 0.8V and 2.0V. Input AC drive levels are 0.45V and 2.4V, unless otherwise specified.
 - 2. $\overline{\text{OE}}$ may be delayed up to t_{CE} t_{OE} after the falling edge of $\overline{\text{CE}}$ without impact on t_{CE} .
 - 3. \overline{OE} may be delayed up to t_{ACC} t_{OE} after the address is valid without impact on t_{ACC}.
 - 4. This parameter is only sampled and is not 100% tested.
 - 5. Output float is defined as the point when data is no longer driven.



11. Input Test Waveforms and Measurement Levels



12. Output Test Load



13. Pin Capacitance

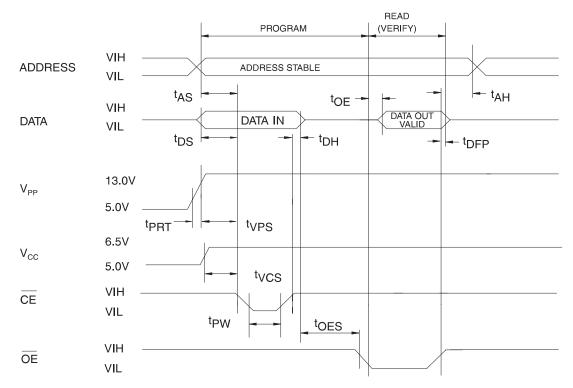
f = 1 MHz, T = $25^{\circ} C^{(1)}$

Symbol	Тур	Мах	Units	Conditions
C _{IN}	4	8	pF	$V_{IN} = 0V$
C _{OUT}	8	12	pF	$V_{OUT} = 0V$

Note: 1. Typical values for nominal supply voltage. This parameter is only sampled and is not 100% tested.



14. Programming Waveforms⁽¹⁾



- Notes: 1. The Input Timing Reference is 0.8V for $\rm V_{IL}$ and 2.0V for $\rm V_{IH}.$
 - 2. t_{OE} and t_{DFP} are characteristics of the device but must be accommodated by the programmer.
 - When programming the AT27C040 a 0.1 μF capacitor is required across V_{PP} and ground to suppress spurious voltage transients.





15. DC Programming Characteristics

 $T_{A} = 25 \pm 5^{\circ}C, V_{CC} = 6.5 \pm 0.25V, V_{PP} = 13.0 \pm 0.25V$

			Limits		
Symbol	Parameter	Test Conditions	Min	Max	Units
ILI	Input Load Current	$V_{IN} = V_{IL}, V_{IH}$		±10	μA
V _{IL}	Input Low Level		-0.6	0.8	V
V _{IH}	Input High Level		2.0	V _{CC} + 0.7	V
V _{OL}	Output Low Voltage	I _{OL} = 2.1 mA		0.4	V
V _{OH}	Output High Voltage	I _{OH} = -400 μA	2.4		V
I _{CC2}	V_{CC} Supply Current (Program and Verify)			40	mA
I _{PP2}	V _{PP} Supply Current	$\overline{CE} = V_{IL}$		20	mA
V _{ID}	A9 Product Identification Voltage		11.5	12.5	V

16. AC Programming Characteristics

 $T_{A} = 25 \pm 5^{\circ}C, \ V_{CC} = 6.5 \pm 0.25V, \ V_{PP} = 13.0 \pm 0.25V$

			Lir	nits	
Symbol	Parameter	Test Conditions ⁽¹⁾	Min	Max	Units
t _{AS}	Address Setup Time		2		μs
t _{OES}	OE Setup Time		2		μs
t _{DS}	Data Setup Time	Input Rise and Fall Times: (10% to 90%) 20 ns	2		μs
t _{AH}	Address Hold Time		0		μs
t _{DH}	Data Hold Time	Input Pulse Levels:	2		μs
t _{DFP}	OE High to Output Float Delay ⁽²⁾	0.45V to 2.4V	0	130	ns
t _{VPS}	V _{PP} Setup Time	Input Timing Reference Level:	2		μs
t _{VCS}	V _{CC} Setup Time	0.8V to 2.0V	2		μs
t _{PW}	CE Program Pulse Width ⁽³⁾	Output Timing Reference Level:	95	105	μs
t _{OE}	Data Valid from $\overline{OE}^{(2)}$	0.8V to 2.0V		150	ns
t _{PRT}	V _{PP} Pulse Rise Time During Programming		50		ns

Notes: 1. V_{CC} must be applied simultaneously or before V_{PP} and removed simultaneously or after V_{PP}

This parameter is only sampled and is not 100% tested. Output Float is defined as the point where data is no longer driven – see timing diagram.

3. Program Pulse width tolerance is 100 $\mu sec \pm 5\%.$

17. Atmel's AT27C040 Integrated Product Identification Code

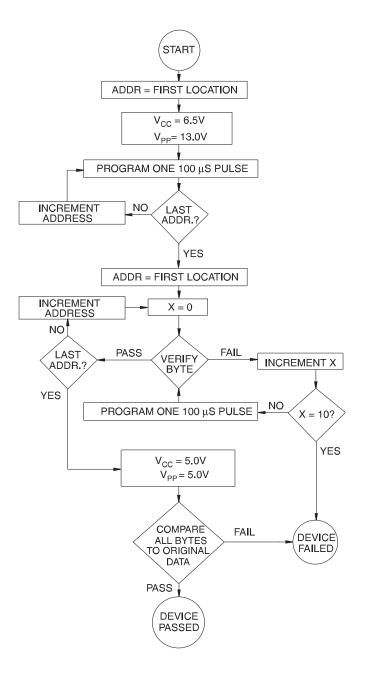
		Pins								
Codes	A0	07	O 6	O 5	04	O3	O2	01	00	Hex Data
Manufacturer	0	0	0	0	1	1	1	1	0	1E
Device Type	1	0	0	0	0	1	0	1	1	0B

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18. Rapid Programming Algorithm

A 100 μ s \overline{CE} pulse width is used to program. The address is set to the first location. V_{CC} is raised to 6.5V and V_{PP} is raised to 13.0V. Each address is first programmed with one 100 μ s \overline{CE} pulse without verification. Then a verification/reprogramming loop is executed for each address. In the event a byte fails to pass verification, up to 10 successive 100 μ s pulses are applied with a verification after each pulse. If the byte fails to verify after 10 pulses have been applied, the part is considered failed. After the byte verifies properly, the next address is selected until all have been checked. V_{PP} is then lowered to 5.0V and V_{CC} to 5.0V. All bytes are read again and compared with the original data to determine if the device passes or fails.



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19. Ordering Information

19.1 Standard Package

	I _{CC} (mA)				
t _{ACC} (ns)	Active	Standby	Ordering Code	Package	Operation Range
			AT27C040-70JI	32J	Industrial
70	30	0.1	AT27C040-70PI	32P6	(-40° C to 85° C)
			AT27C040-70TI	32T	(-40 C (0 85 C)
			AT27C040-90JI	32J	Industrial
90	30	0.1	AT27C040-90PI	32P6	Industrial
			AT27C040-90TI	32T	(-40° C to 85° C)

Note:

Not recommended for new designs. Use Green package option.

19.2 Green Package Option (Pb/Halide-free)

	I _{CC} (mA)				
t _{ACC} (ns)	Active	Standby	Ordering Code	Package	Operation Range
70	30	0.1	AT27C040-70JU	32J	Industrial (-40° C to 85° C)
			AT27C040-70PU	32P6	
			AT27C040-70TU	32T	
90	30	0.1	AT27C040-90JU	32J	Industrial
			AT27C040-90PU	32P6	
			AT27C040-90TU	32T	(-40° C to 85° C)

Package Type				
32J	32-lead, Plastic J-leaded Chip Carrier (PLCC)			
32P6	32-lead, 0.600" Wide, Plastic Dual Inline Package (PDIP)			
32T	32-lead, Plastic Thin Small Outline Package (TSOP)			

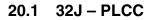
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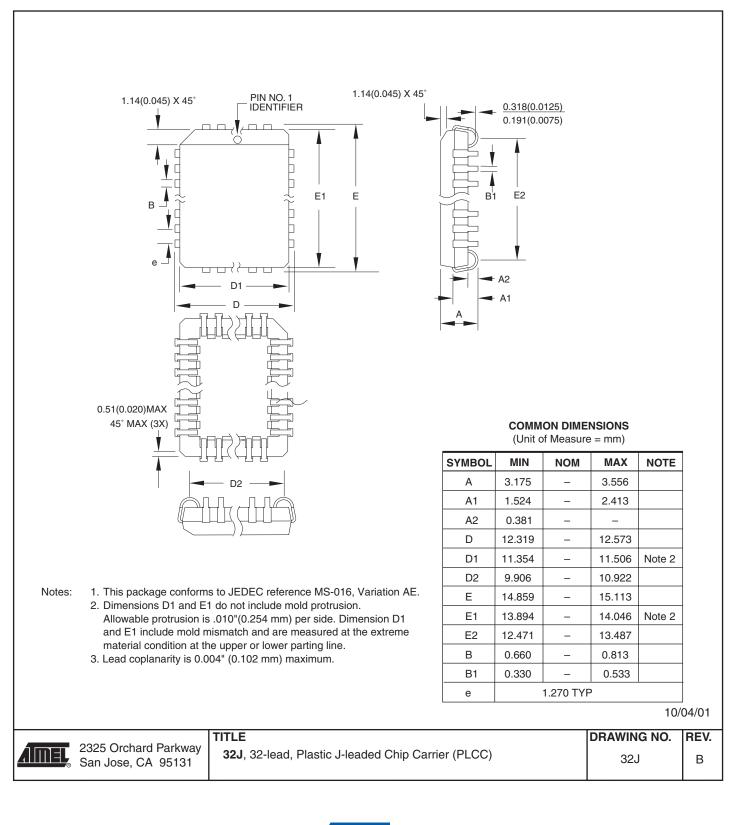
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20. Package Information





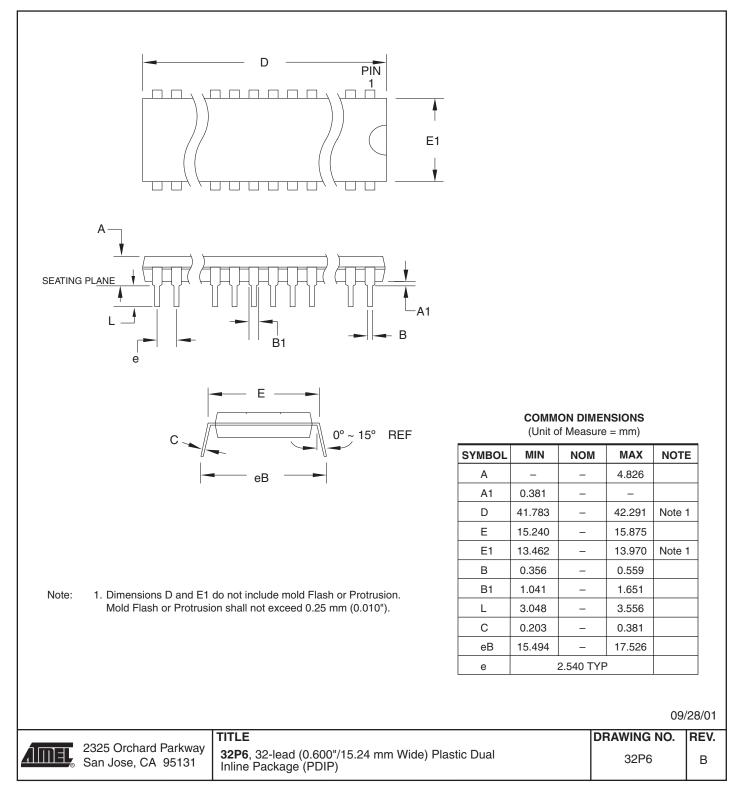
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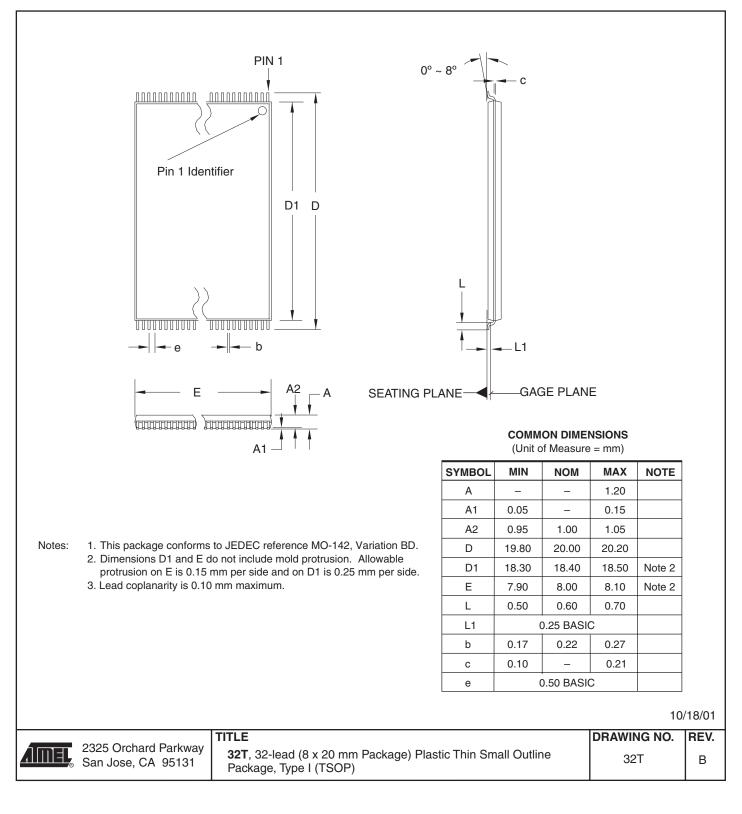
20.2 32P6 - PDIP



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20.3 32T – TSOP



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